



# US/Japan Collaboration Beam Monitor Meeting

## Thursday, 26 March 2015

### Session 1 - Huddle (13:00 - 15:00)

time	[id] title	presenter
13:00	[6] SSEM/SEM (Segmented Secondary Emission Monitor)	Dr FRIEND, Megan
13:35	[7] BIF (Beam Induced Fluorescence) Monitor: Overview and Design	Dr FRIEND, Megan
14:10	[8] BIF (Beam Induced Fluorescence) Monitor: MPPC Tests and Material Test Plans	BRONNER, C.
14:40	[9] Secondary Particle Monitor Using CT (Current Transformer): Conceptual Design	NAKADAIRA, T.